



Test Report:

2W04841

Applicant:

Samsung Electro-Mechanics CO, Ltd.
314, Maetan-3 Dong, Paldal-Gu, Suwon,
Kyungki-Do
Korea

**Equipment Under Test:
(EUT)**

SDR4000K
27MHz Low Power Wireless Keyboard

FCC ID:

In Accordance With:

FCC 47 CFR Part 15, Subpart C: 2000

Tested By:

Nemko Canada Inc.
303 River Road, R.R. 5
Ottawa, Ontario K1V 1H2

Authorized By:

John Harrington, RF Group Manager

Date:

12 April 2002

Total Number of Pages:

11

Table Of Contents

Section 1. Summary Of Test Results.....3

Section 2. General Equipment Specification5

Section 3. Radiated Emissions.....7

Section 4. Block Diagrams.....10

Section 5. Test Equipment List11

Section 1. Summary Of Test Results

General

All measurements are traceable to national standards.

These tests were conducted on a sample of the equipment for the purpose of demonstrating compliance with FCC Part 15, Subpart C for low power devices. All tests were conducted using measurement procedure ANSI C63.4-1992. Radiated Emissions were made on an open area test site. A description of the test facility is on file with the FCC.

THIS TEST REPORT RELATES ONLY TO THE ITEM(S) TESTED.

THE FOLLOWING DEVIATIONS FROM, ADDITIONS TO, OR EXCLUSIONS FROM THE
TEST SPECIFICATIONS HAVE BEEN MADE.

See " Summary of Test Data".

TESTED BY: Glen Westwell, Wireless Technologist DATE: 10 April 2002

Nemko Canada Inc., a testing laboratory, is accredited by the Standards Council of Canada. The tests included in this report are within the scope of this accreditation. The results apply only to the samples tested.

Nemko Canada Inc. authorizes the above named company to reproduce this report provided it is reproduced in its entirety and for use by the company's employees only.

Any use which a third party makes of this report, or any reliance on or decisions to be made based on it, are the responsibility of such third parties. Nemko Canada Inc. accepts no responsibility for damages, if any, suffered by any third party as a result of decisions made or actions based on this report.

This report applies only to the items tested.

EQUIPMENT: SDR4000K

Summary Of Test Data

Name Of Test	Para. No.	Result
Powerline Conducted Emissions	15.207	N/A
Radiated Emissions (Fundimental)	15.227	Complies
Radiated Emissions (Spurious)	15.209	Complies

Footnotes For N/A's:**Test Conditions:**

Indoor Temperature: 22°C
 Humidity: 44%

Outdoor Temperature: 9°C
 Humidity: 46%

Section 2. General Equipment Specification

Manufacturer: Samsung Electro-Mechanics CO, Ltd.

Model No.: SDR4000K

Serial No.: None

Date Received In Laboratory: 8 April 2002

Nemko Identification No.: #4

Transmit Frequency: 27.145MHz

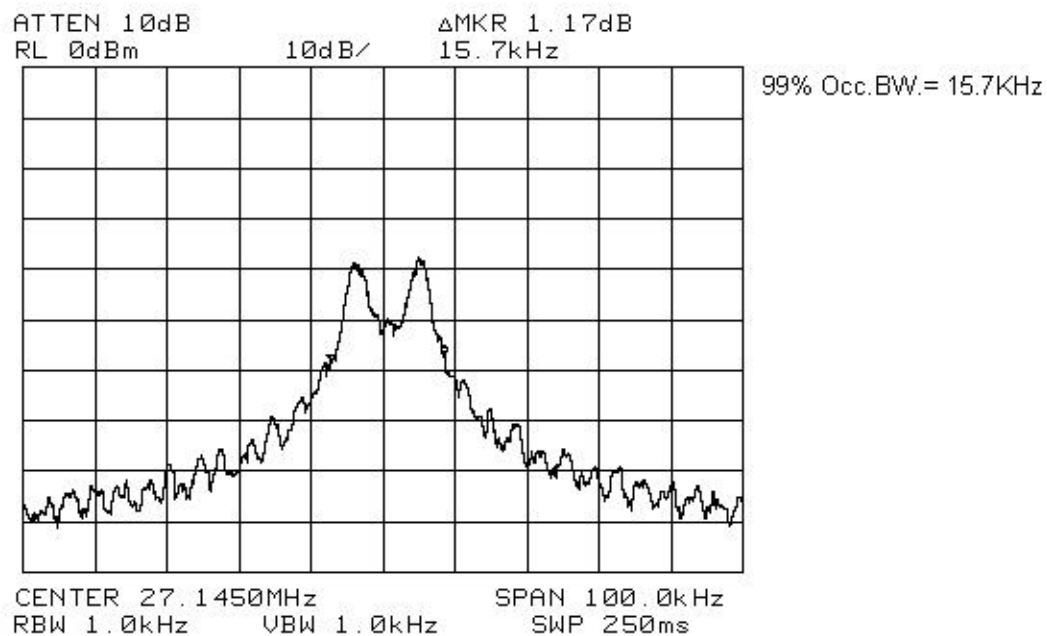
Modulation: FSK

Rated Output Power: -12dBm (.063mW)

Input Power Source: 3Vdc

Emission Designator: 15K7F1D

EQUIPMENT:SDR4000K



EQUIPMENT:SDR4000K

Section 3. Radiated Emissions

Para. No.: 15.209

15.227

Test Performed By: Glen Westwell	Date of Test: 9April 2002
---	----------------------------------

Minimum Standard: 15.227, 80dBuV/M at 3m.**Minimum Standard:** 15.209,

Fundamental (MHz)	Field Strength (μV/m)	Field Strength (dBμV)
0.009 - 0.490	2400/F(kHz) @ 300m	—
0.490 - 1.705	24000/F(kHz) @ 30m	—
1.705 - 30	30 @ 30m	—
30 - 88	100	40.0
88 - 216	150	43.5
216 - 960	200	46.0
Above 960	500	54.0

Test Results: Complies.**Measurement Data:** See attached table.

EQUIPMENT:SDR4000K

Test Data - Radiated Emissions

Test Distance (meters) : 3		Range: A		Receiver: EVSP		RBW(kHz): 120		Detector: Q-Peak	
Freq. (MHz)	Ant.	Pol. (V/H)	RCVD Signal (dBμV/m)	Ant. Factor (dB)**	Amp. Gain (dB)***	Dist. Corr. (dB)	Field Strength (dBμV/m)	Limit (dBμV/m)	Margin (dB)
27.145	BC1	V	48.8	14			62.8	80.0	17.2
27.145	BC1	H	36.3	14			50.3	80.0	29.7
81.435	BC1	V	7.4	8.4			15.8	40.0	24.2
81.435	BC1	H	N.D.				N.D.	40.0	----
108.58	BC1	V	10.3	11.2			21.5	43.5	22.0
108.58	BC1	H	N.D.				N.D.	43.5	----
135.725	BC1	V	10.2	13.9			24.1	43.5	19.4
135.725	BC1	H	N.D.				N.D.	43.5	----
162.87	BC1	V	12.2	13.8			26.0	43.5	17.5
162.87	BC1	H	N.D.				N.D.	43.5	----

Notes:
B/C = Biconical, B/L = Biconilog, L/P = Log-Periodic, H = Horn, D/P = Dipole
* Re-measured using dipole antenna.
** Includes cable loss when amplifier is not used.
*** Includes cable loss.
() Denotes failing emission level.
N.D. = Not Detected

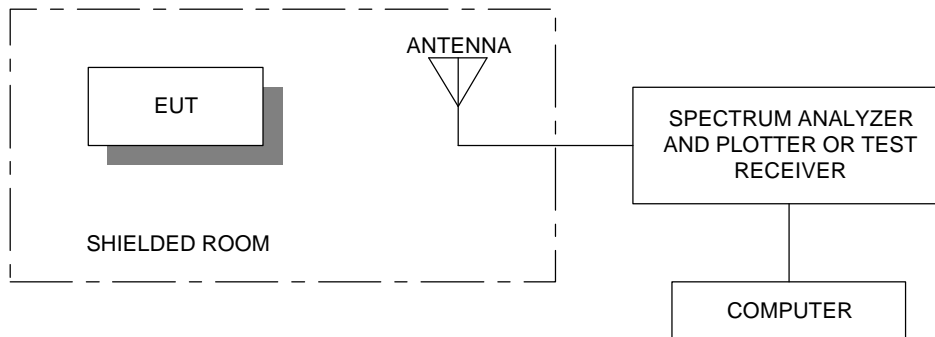
All emissions were searched up to the 10th harmonic.

EQUIPMENT:SDR4000K

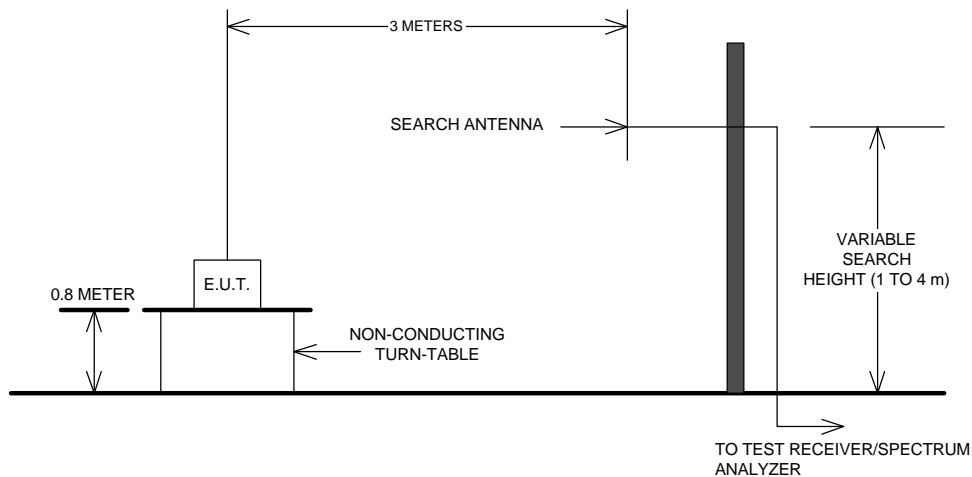


Section 4. Block Diagrams

Radiated Prescan



Test Site For Radiated Emissions



EQUIPMENT:SDR4000K

Section 5. Test Equipment List

CAL CYCLE	EQUIPMENT	MANUFACTURER	MODEL	SERIAL	LAST CAL.	NEXT CAL.
1 Year	Spectrum Analyzer-1	Hewlett Packard	8566B	2311A02238	27 Nov 2001	27 Nov 2002
1 Year	Spectrum Analyzer Display-1	Hewlett Packard	8566B	2314A04759	27 Nov 2001	27 Nov 2002
1 Year	Quasi-peak adapter-1	Hewlett-Packard	85650A	2043A00302	27 Nov 2001	27 Nov 2002
1 Year	Receiver	Rohde & Schwarz	ESVP	892661/014	19 Sep 2001	19 Sep 2002
1 Year	Biconical 2	EMCO	3109	2708	Aug. 28/01	Aug. 28/02